

# MR2003C LDMOS TRANSISTOR

Document Number: MR2003C  
Preliminary Datasheet V1.1

## 30W, 28V High Power RF LDMOS FETs

### Description

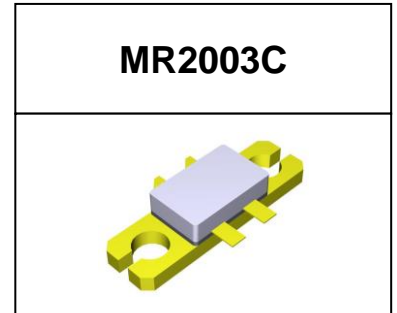
The MR2003C is a 30-watt, unmatched LDMOS FETs, designed for Wide-band and Mobile radio applications with frequencies under 2000 MHz. It can be used in Class AB/B and Class C for all typical modulation formats.

**It can also operate at lower voltage down to 12V with decrease power capability.**

- Typical Performance (On Innogration fixture with device soldered):

$V_{DD} = 28$  Volts,  $I_{DQ} = 200$  mA, CW.

Frequency	Gp (dB)	P <sub>-1dB</sub> (W)	$\eta_D@P_{-1}$ (%)
1000 MHz	22	30	65



**MR2003C**

### Notice:

**It is recommended to operate this device only below 24V like 14V,12.5V etc, if operation band is below 500MHz.**

### Features

- High Efficiency and Linear Gain Operations
- Integrated ESD Protection
- Excellent thermal stability, low HCI drift
- Large Positive and Negative Gate/Source Voltage Range for Improved Class C Operation
- Pb-free, RoHS-compliant

### Suitable Applications

- 30-88MHz (Ground communication)
- 54-88MHz (TV VHF I)
- 88-108MHz (FM)
- 118 -140MHz (Avionics)
- 136-174MHz (Commercial ground communication)
- 160-230MHz (TV VHF III)
- 30-512MHz (Jammer, Ground/Air communication)
- 470-860MHz (TV UHF)

**Table 1. Maximum Ratings**

Rating	Symbol	Value	Unit
Drain--Source Voltage	$V_{DSS}$	+65	Vdc
Gate--Source Voltage	$V_{GS}$	-10 to +10	Vdc
Operating Voltage	$V_{DD}$	+32	Vdc
Storage Temperature Range	$T_{stg}$	-65 to +150	°C
Case Operating Temperature	$T_c$	+150	°C
Operating Junction Temperature	$T_j$	+225	°C

**Table 2. Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case $T_C = 85^\circ\text{C}$ , $T_J = 200^\circ\text{C}$ , DC test	$R_{\theta JC}$	1.0	°C/W

**Table 3. ESD Protection Characteristics**

Test Methodology	Class
Human Body Model (per JESD22--A114)	Class 2

**Table 4. Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
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## DC Characteristics (per half section)

Drain-Source Voltage $V_{GS}=0, I_{DS}=1.0mA$	$V_{(BR)DSS}$	65	70		V
Zero Gate Voltage Drain Leakage Current ( $V_{DS} = 28 V, V_{GS} = 0 V$ )	$I_{DSS}$	---	---	1	$\mu A$
Gate--Source Leakage Current ( $V_{GS} = 9 V, V_{DS} = 0 V$ )	$I_{GSS}$	---	---	1	$\mu A$
Gate Threshold Voltage ( $V_{DS} = 28V, I_D = 600 \mu A$ )	$V_{GS(th)}$	---	2.17	---	V
Common Source Input Capacitance ( $V_{GS} = 0V, V_{DS} =14 V, f = 1 MHz$ )	$C_{ISS}$		15.7		pF
Common Source Output Capacitance ( $V_{GS} = 0V, V_{DS} =14 V, f = 1 MHz$ )	$C_{OSS}$		6.0		pF
Common Source Feedback Capacitance ( $V_{GS} = 0V, V_{DS} =14 V, f = 1 MHz$ )	$C_{RSS}$		0.42		pF
Common Source Input Capacitance ( $V_{GS} = 0V, V_{DS} =28 V, f = 1 MHz$ )	$C_{ISS}$		16.0		pF
Common Source Output Capacitance ( $V_{GS} = 0V, V_{DS} =28 V, f = 1 MHz$ )	$C_{OSS}$		4.6		pF
Common Source Feedback Capacitance ( $V_{GS} = 0V, V_{DS} =28 V, f = 1 MHz$ )	$C_{RSS}$		0.38		pF

**Functional Tests** (On Demo Test Fixture, 50 ohm system)  $V_{DD} = 28 Vdc, I_{DQ} = 200 mA, f = 1000 MHz, CW$  Signal Measurements.

Power Gain	$G_p$		22		dB
Drain Efficiency@P1dB	$\eta_D$		65		%
1 dB Compression Point	$P_{-1dB}$		30		W
Input Return Loss	IRL		-10		dB

**Load Mismatch (In Innogration Test Fixture, 50 ohm system):**  $V_{DD} = 28 Vdc, I_{DQ} = 100 mA, f = 1000 MHz$

VSWR 10:1 at 30W pulse CW Output Power	No Device Degradation
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## Package Outline

Flanged ceramic package; 2 mounting holes; 4 leads

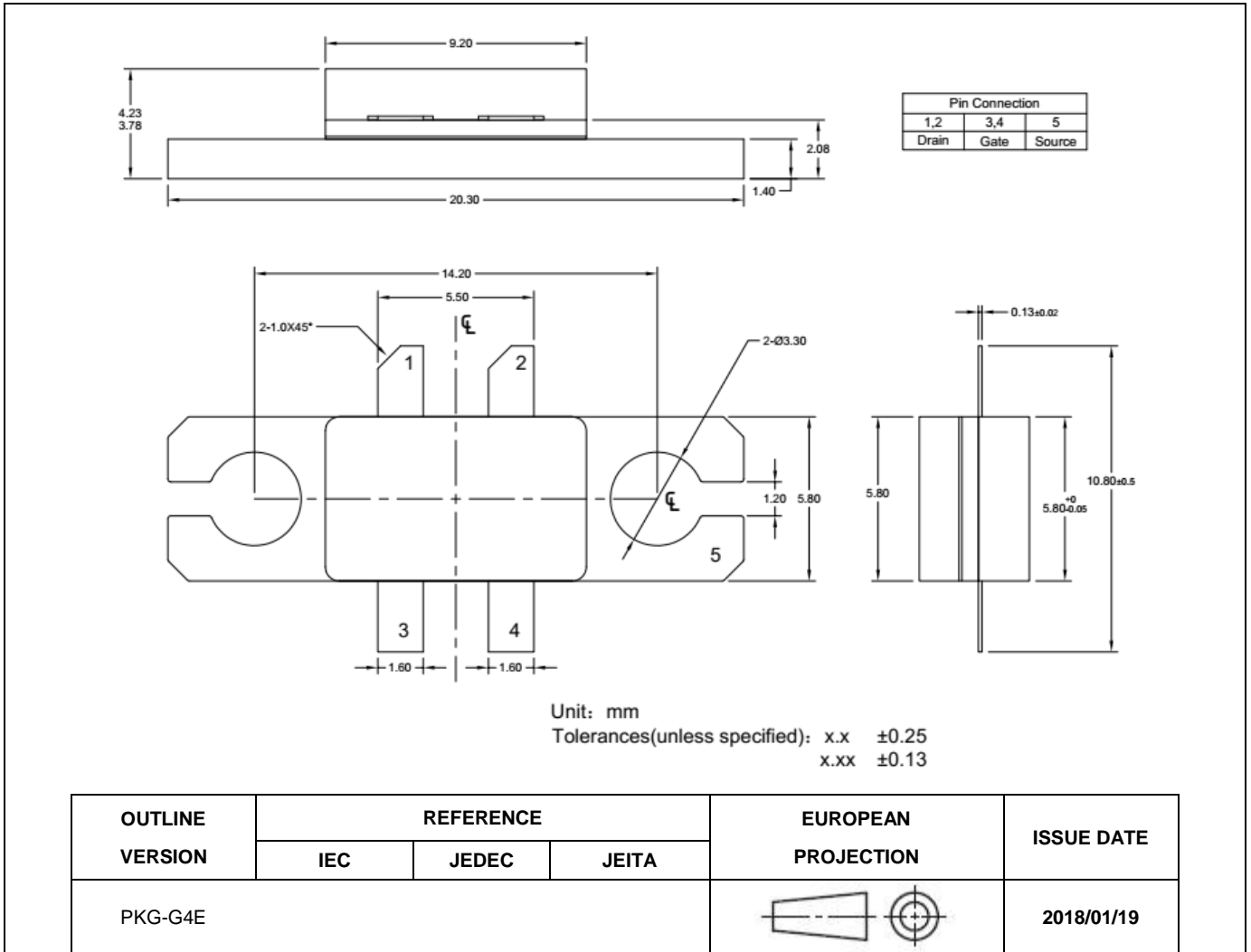


Figure 1. Package Outline PKG-G4E

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## Revision history

Table 5. Document revision history

Date	Revision	Datasheet Status
2018/6/14	Rev 1.0	Preliminary Datasheet
2018/8/2	Rev 1.1	Add notice of below 500MHz operation

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